

Notice of References Cited	Application/Control No. 10/657,492	Applicant(s)/Patent Under Reexamination REE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0042444	03-2004	Edmon et al.	370/352
*	B	US-6,788,675	09-2004	Yang, Jin	370/352
*	C	US-2004/0213204	10-2004	Yang, Jin Young	370/352
*	D	US-7,082,141	07-2006	Sharma et al.	370/493
*	E	US-2004/0264488	12-2004	Yoon et al.	370/412
*	F	US-7,106,723	09-2006	Rabenko, Theodore F	370/352
*	G	US-2007/0070986	03-2007	Rabenko, Theodore F.	370/352
*	H	US-2002/0162116	10-2002	Read et al.	725/106
*	I	US-2003/0145332	07-2003	Furuta, Tetsuro	725/111
*	J	US-6,765,901	07-2004	Johnson et al.	370/352
*	K	US-6,075,784	06-2000	Frankel et al.	370/356
*	L	US-6,304,567	10-2001	Rosenberg, Jonathan David	370/356
*	M	US-2002/0061012	05-2002	Thi et al.	370/352

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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